

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/728,442 | Applicant(s)/Patent Under Reexamination LEMLER ET AL. | |
| | Examiner Djenane M Bayard | Art Unit 2141 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-5,893,905 | 04-1999 | Main et al. | 705/11 |
| | B | US-6,701,345 | 03-2004 | Carley et al. | 709/205 |
| | C | US-6,304,892 | 10-2001 | Bhoj et al. | 709/202 |
| | D | US-6,466,984 | 10-2002 | Naveh et al. | 709/228 |
| | E | US-2003/0187966 | 10-2003 | SINHA, HIMANSHU S. | 709/223 |
| | F | US-6,459,682 | 10-2002 | Elleson et al. | 370/235 |
| | G | US-6,701,342 | 03-2004 | Bartz et al. | 709/200 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.